SDLS006

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- 8-Bit Serial-In, Parallel-Out Shift Registers with Storage
- Choice of 3-State ('LS595) or Open-Collector ('LS596) Parallel Outputs
- · Shift Register Has Direct Clear
- Accurate Shift Frequency: DC to 20 MHz

description

These devices each contain an 8-bit serial-in, parallel-out shift register that feeds an 8-bit D-type storage register. The storage register has parallel 3-state ('LS595) or open-collector ('LS596) outputs. Separate clocks are provided for both the shift register and the storage register. The shift register has a direct-overriding clear, serial input, and serial output pins for cascading.

Both the shift register and storage register clocks are positive-edge triggered. If the user wishes to connect both clocks together, the shift register state will always be one clock pulse ahead of the storage register. SN54LS595, SN54LS596...J OR W PACKAGE SN74LS595, SN74LS596...N PACKAGE

(TOP VIEW)

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SN54LS595, SN54LS596 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection



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schematics of inputs and outputs

logic diagram (positive logic)







 $^\dagger These symbols are in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12. Pin numbers shown are for J, N, and W packages.$

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, Vnc (see Note 1)		
Off state output voltage		5.5 V
Operation free-air temperature range'	SN54LS595, SN54LS596	
Operating nee-an temperature range.	SN74LS595, SN74LS596	0°C to 70°C
Storage temperature range		$\dots - 65^{\circ}C$ to $150^{\circ}C$

NOTE 1: Voltage values are with respect to the network ground terminal.

recommended operating conditions

			SN54LS'			SN74LS'			UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage	· · · · · · · · · · · · · · · · · · ·	4.5	5	5.5	4.75	5	5,25	V
VIH	High-level input voltage		2			2			V
VIL	Low-level input voltage				0.7			0.8	V_
VOH	High-level output voltage	QA thru QH, 'LS596 only			5.5			5.5	V
¹ он	High-level output current	QH			- 1			- 1	mA
		Q _A thru Q _H , 'L\$595 only			- 1			- 2.6	ļ
IOL	Low-level output current	Q _H			8			16	- mA
		Q			12			24	
fSRCK	Shift clock frequency	1	0		20	0		20	MH 2
tw(SRCK)	Duration of shift clock pulse		25			25			ns
tw(RCK)	Duration of register clock pul	SE CONTRACTOR	20			20			ns
tw(SRCLR)	a) Duration of shift clear pulse, low level					20			ns
t _{sti}		SRCLR inactive before SRCK †	20			20			
	Setup time	SER before SRCK 1	20			20			ns
		SRCK † before RCK † (see Note 2)	40			40			113
		SRCLR low before RCK t	40			40			
<u></u> եր	Hold time	SER after SRCK 1	0	·		0			ns
	Operating free-air temperatur	e	- 55		125	0		70	°C

NOTE 2: This setup time ensures the register will see stable data from the shift-register outputs. The clocks may be connected together, in which case the storage register state will be one clock pulse behind the shift register.



PARAMETER				SN54LS'			SN74LS'				
		TEST CONDITIONS [†]			TYP‡	MAX	MIN	TYP‡	MAX	UNIT	
		V _{CC} = MIN, I ₁ = - 18 mA				- 1.5	[- 1.5	V	
, 'LS595 Q		V _{CC} = MIN, V _{IH} = 2 V,	¹ OH = -1 mA	2.4	3.2					v	
∨он	QH'	VIL = MAX	$I_{OH} = -2.6 \text{ mA}$ $I_{OH} = -1 \text{ mA}$	2.4	3.2		2.4	3.1		v	
юн	'L\$596 Q	$V_{CC} = MIN, V_{IH} = 2V, V_{IH}$	IL = MAX, VOH = 5.5 V			0.1	<u> </u>		0.1	mA	
Q	V		I _{OL} - 12 mA		0.25	0.4		0.25	0.4		
VOL		$V_{CC} = MIN, V_{IH} = 2V,$	1 _{OL} = 24 mA	ļ				0.35	0.5	v	
02		VIL = MAX	IOL = 8 mA		0.25	0.4	<u> </u>	0.25	0.4		
IOZH	'LS595 Q	V _{CC} = MAX, V _{1H} = 2 V, V				20		0.55	20	μΑ	
OZL	'LS595 Q	V _{CC} = MAX, V _{1H} = 2 V, V _I		<u> </u> -		- 20			- 20	μA	
Ч	•	$V_{CC} = MAX, V_1 = 7V$				0.1			0.1	.1 mA	
Чн		V _{CC} - MAX, V ₁ - 2.7 V		[20	[20	μA	
	SER	Vcc = MAX, Vi = 0.4 V			_	- 0.4			- 0.4	mΑ	
All othe		VCC - MAX, V) - 04 V				- 0.2			- 0.2	A	
IOS §	'LS595 Q	$V_{CC} = MAX, V_{O} = 0 V$		- 30		130	- 30		- 130	mА	
'OS 9 QH'				- 20		- 100	- 20		- 100		
'LS595					33	50		33	50	mА	
ICCH	'L\$596	V _{CC} = MAX.		30	45		30	45			
ICCL .	'LS595	All possible inputs grounded,			42	65		42	65	mA	
	'L\$596	All outputs open			36	55		36	55		
lccz	'L S 595				44	65		44	65	mΑ	

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

+ For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions,

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T All typical values are at V_{CC} = 5 V, T_A = 25°C. § Not more than one output should be shorted at a time, and duration of the short-circuit should not exceed one second.



PARAMETER	FROM	TO (OUTPUT)	TEST CONDITIONS		'LS595			'LS596			UNIT
	(INPUT)		IESICON	MIN	TYP	MAX	MIN	ΤΥΡ	MAX		
tPLH	SRCKT		5 110	0 - 20 - 5	1	12	18		14	21	ns
^t PHL		°н′	$\mathbf{R}_{L} = 1 k \Omega_{r}$	C _L = 30 pF		17	25		20	30	ns
^t PLH	RCK 1	Q _A thru Q _H	$R_{L} = 667 \Omega$, $C_{L} = 45 pF$		12	18		28	42	ns	
^t PHL				CL = 45 pF		24	35		24	35	ns
tpzh		Q _A thru Q _H				20	30				n:s
tPZL		· · ·					25	38		_	
^t PHZ	<u>G</u> t	Q _A thru Q _H	$R_1 = 667 \Omega_c$	C _I = 5 pF		20	30				ns
^t PLZ			UT - 001 77'	CL - 5 PF		25	38		-		ns
^t PLH	<u>G</u> †	QA thru QH D - CC2 O	$R_1 = 667 \Omega_2$, C _L = 45 pF	1				40	60	n\$
^t PHL	Ğ∔	Q _A thru Q _H	ni - 00/11,						25	38	ns
^t PHL	SRCLR +	QH'	$R_{L} = 1 k\Omega$,	CL = 30 pF	-	24	35		24	35	ns

switching characteristics, V_{CC} = 5 V, T_A = 25° C (see note 3)

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.



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